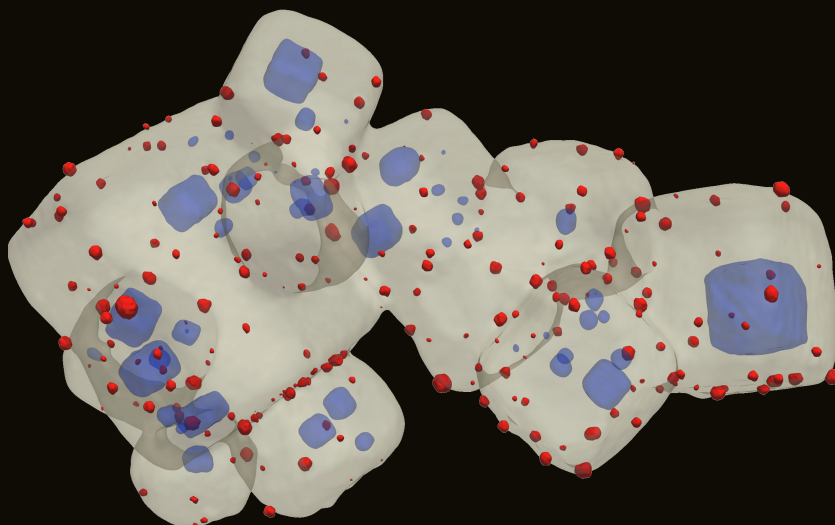
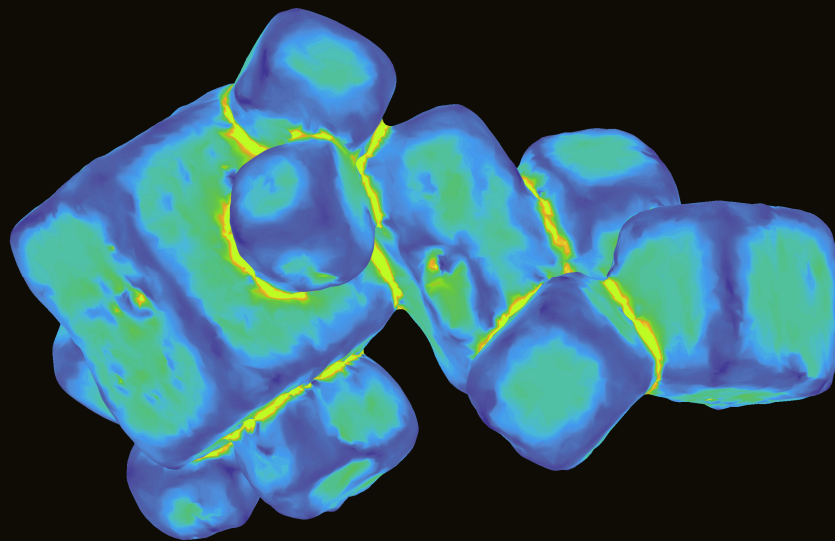


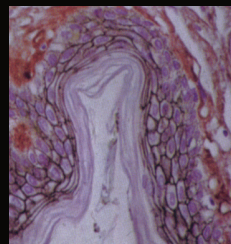
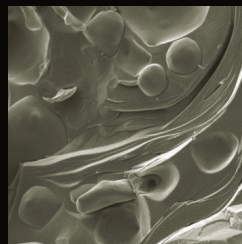
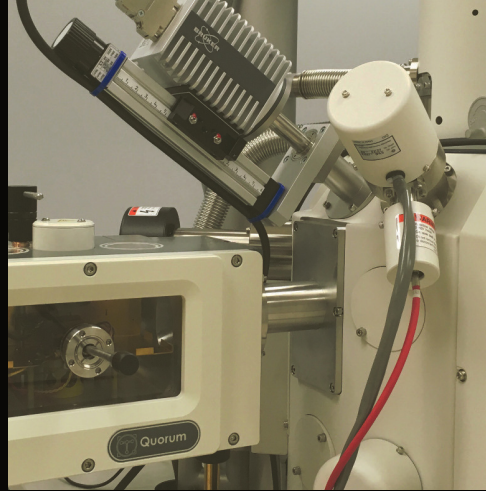
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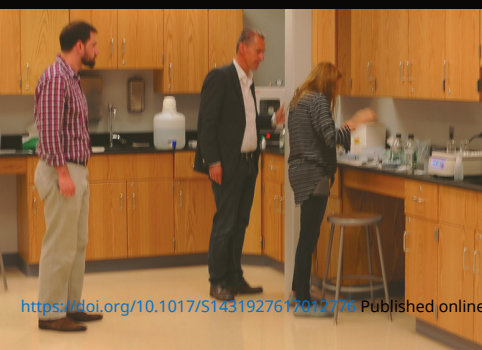
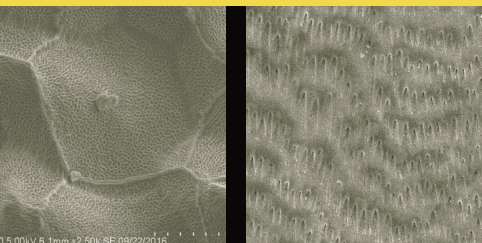
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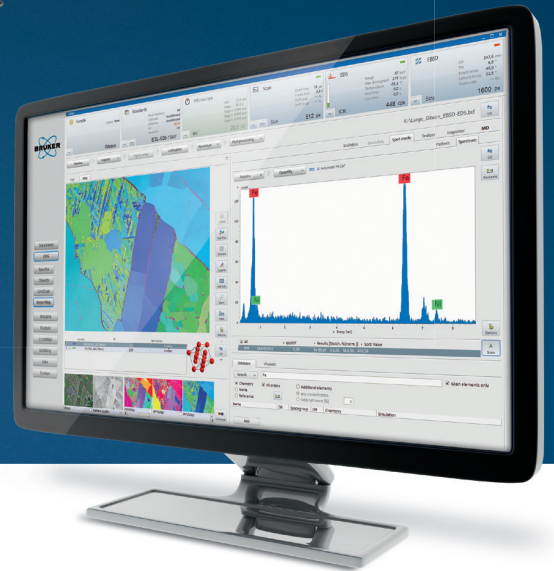
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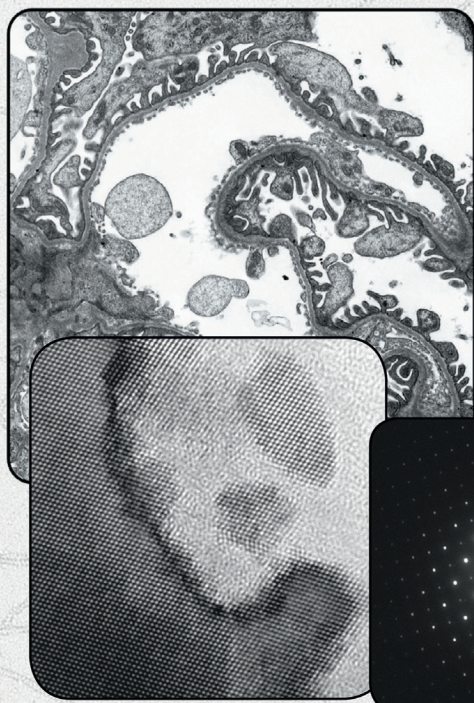
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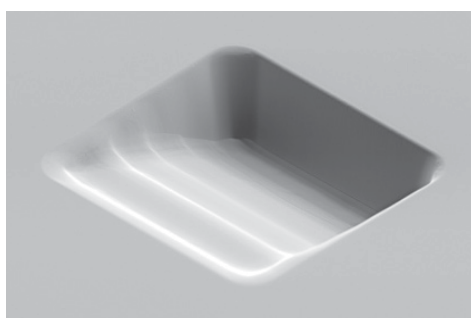
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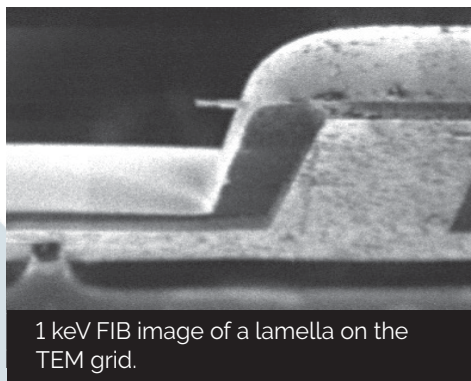
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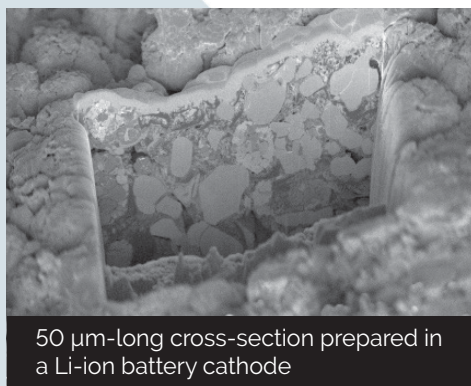
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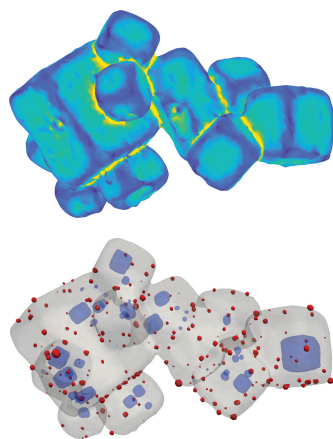
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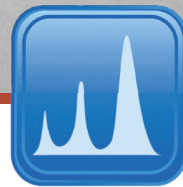
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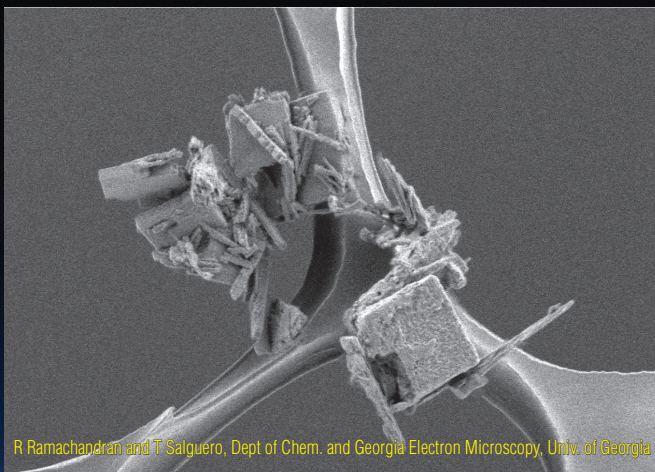
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1: Guaranteed; 2: M.Konno, et.al., Ultramicroscopy 145 (2013)



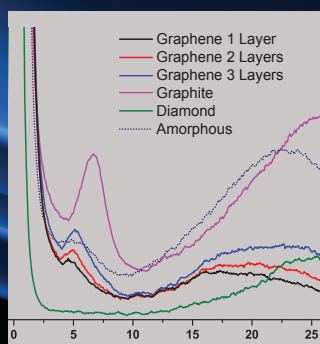
R.Ramachandran and T.Salguero, Dept of Chem. and Georgia Electron Microscopy, Univ. of Georgia

Deceleration technology at 300 V and DOF correction

High-Resolution, Low-Voltage, Analytical STEM/SEM

- Imaging from 100 V to 30,000 V
- 0.7 sr for EDX
- Elemental maps at $\geq 11,000$ pixels/s with Hitachi's own EELS

This new breed of microscopes delivers for research aiming at nanotechnology, materials science, and life sciences.



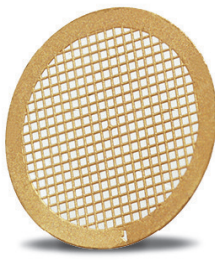
EELS spectra of all C allotropes
Note Plasmon shift with increasing number in Graphene layers



*Hitachi SU9000
FE-STEM/SEM*

Think Outside the Lab

The C-flat™ Advantage



C-flat™ leads to better data sets.

Made with patented technology, C-flat™ provides an ultra-flat surface that results in better particle dispersion and more uniform ice thickness. Patterning is done using deep-UV projection lithography, ensuring the most accurate and consistent hole shapes and sizes down to submicron features. The precise methods by which C-flat™ is manufactured eliminate artifacts such as excess carbon and edges around holes.

C-flat™ is affordable

C-flat™ is available in 25, 50, and 100 packs at a per-grid price less than competing products.

Applications

C-flat holey carbon grids provide the ideal specimen support to achieve high resolution data in cryoTEM making C-flat the perfect choice for:

- Single particle analysis
- Cryo electron tomography
- Automated TEM analysis

...EMS has it!

CONTACT US FOR MORE INFORMATION...

Electron Microscopy Sciences

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email: sgkcck@aol.com
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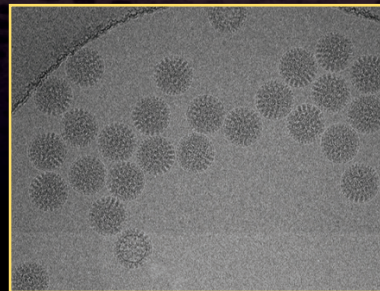
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the premier holey carbon grid for
cryo-transmission electron microscopy

C-FLAT™

Holey Carbon and Gold Grids for Cryo-TEM

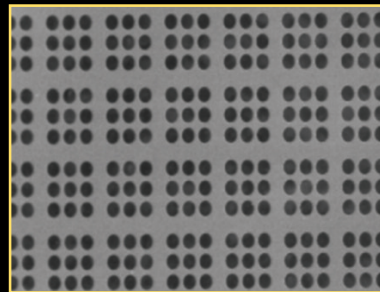
C-Flat™ is a clean, ultra-flat holey carbon film TEM grid primarily used for Cryo TEM and Automated TEM. With a variety of available hole diameters, mesh size, film thicknesses, and mesh material, there is a C-Flat™ product suitable for any application in the TEM.



Frozen-hydrated Bacteriophage Capsid
(data acquired on CF-1.2/1.4-4C).

Consistent

Researchers around the world have reported that the ultra-flat surface of C-flat™ leads to even ice thickness and uniform particle distribution, allowing for superior 3-D reconstructions. 2 µm hole sizes are standard, but various hole sizes are available to accommodate different particle sizes and magnifications.



Compatible

C-flat™ provides a regular array of analysis sites compatible with automated data collection software such as Legimon. This compatibility, in combination with the more uniform ice thickness and particle distribution reported by numerous researchers, results in more high-quality target sites per grid.



Clean

C-Flat™ uses no plastics or polymers in its production. This means C-Flat™ is shipped clean, so it's ready to use out of the box and requires no solvent washing steps prior to use, leading to less breakage of the holey carbon film.

Expanded Product Line

The breadth of applications in cryoTEM necessitate a wide range of holey carbon film patterns. And now, with the recent expansion of the product line, a C-flat™ holey carbon film is available for almost any application.